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Spatially resolved EELS with an in-column Omega filter – from distorted recordings to corrected results

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Introduction

Spatially resolved EELS (SR-EELS) [1] is a technique to preserve one-dimensional spatial information when recording EEL spectra. Using SR-EELS, many EEL spectra are recorded in parallel as a function of one spatial coordinate, perpendicular to the energy dispersive direction. This method is useful for investigating specimens like interfaces and layer systems. We will show that the used in-column Omega filter [2] of a Zeiss Libra 200FE introduces distortions to the SR-EELS images and we present a work flow to entirely correct these distortions.

A layer system of iron and chromium on silicon oxide and silicon is used to benchmark the method and the image processing. All steps of image processing are performed by EFTEMj [3], a plugin for the open source software Fiji [4], which is written in Java.

SR-EELS in 4 steps

Here we describe the workflow of creating a SR-EELS data set.

- a) Rotate the specimen to get the correct orientation: The layer boundaries have to be parallel to the energy dispersive direction.
- b) We use a slit aperture at the filter entrance plane. Compared with a round aperture the intensity along the lateral axis is uniform, but we lose intensity as the slit is narrower. c) Switch to the EELS mode. Operating with the default energy filter settings, the image at the energy dispersive plane is strongly distorted. Lateral information is visible, but not usable for quantitative measurements. This image can be used to create an EEL spectrum (see red line at the plot on the right). d) After optimising the filter parameters, the image at the energy dispersive plane shows much less distortion (see the figure on the top right). Using our image processing software (EFTEMj [3]), we can remove the remaining distortion and obtain the final result. The inset plot shows the background subtracted element signals (processed with CSI [5]). The shown interval corresponds to the coloured regions of the SR-EELS data set.



MC2015 Göttingen, IM4.P108





A dataset recorded with optimised energy filter parameters (QSinK7 = -15%). The image is cropped to remove unnecessary parts at the top and the bottom. The overlaid, horizontal lines highlight the remaining distortions.

EEL spectra showing the L-edges of iron and chromium. The red and the blue spectra are plotted with the same energy dispersion. By optimising the energy filter for SR-EELS, the energy dispersion changes (blue). The black spectrum shows the same data as the blue one, but the energy dispersion has been corrected. The match with the red spectrum is





https://github.com/m-entrup/MC2015-Poster

The characterisation is done by shifting a small aperture at the filter entrance plane along the long axis of the slit aperture.

QSinK7 = -15%

On the left 5 TEM image are shown that display the position of the 100 μ m aperture. On the right two superpositions of the 5 resulting SR-EELS images are shown. The default energy filter parameters and the optimised parameters are compared to each other.

